## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: 04/2018 to 03/2019

Based on structura	l similarity
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Supplier		User Part Number						
Nexperia B.V. Name of Laboratory Assembly reliability labs AEC-Q101 Test		BF824 Part Description						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
			TEST					
	Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# 2	Preconditioning	Reflow soldering	3 cycles	663	47550	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# 5	Bias	reverse voltage	1000 hours	154	12320	0		
	тс	JESD22-A104						
# 7	Temperature Cycling	-55 °C to Tjmax, not to exceed 150°C	1000 cycles	139	11125	0		
		JESD22-A102						
	AC	Tamb = 121 °C, RH = 100 %						
# 8	Autoclave	Pressure = 205 kPa (29.7 psia)	96 hours	136	10880	0		
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR > 80 % of						
# 9	Temperature Reverse Bias	rated reverse voltage	1000 hours	139	11125	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure $\Delta Tj$ =						
# 10	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	139	11120	0		
	RSH	JESD22-A111						
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s	110	3300	0		
	SD	J-STD-002						
# 21	Solderability	Test method B and D		264	2640	0		

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, AEC-Q101 Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia	Small Signal Bipolar				
DHAM	Transistor	12320	0	0,34	2,90E+09

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